

2-Propanol
CMOS

(iso-propyl alcohol)



Material No.: 9079-05
Batch No.: 0000000162
Manufactured Date: 2012/04/16

Certificate of Analysis

Test	Specification	Result
Assay (CH ₃ CHOHCH ₃)	>= 99.5 %	100.0
Color (APHA)	<= 10	5
Residue after Evaporation	<= 4 ppm	< 1
Solubility in H ₂ O	Passes Test	PT
Water (H ₂ O)(by Karl Fischer titrn)	<= 0.05 %	0.01
Acidity (µeq/g)	<= 0.2	< 0.2
Alkalinity (µeq/g)	<= 0.1	< 0.1
Chloride (Cl)	<= 0.1 ppm	< 0.1
Phosphate (PO ₄)	<= 0.3 ppm	< 0.3
Trace Impurities –Aluminum (Al)	<= 50.0 ppb	< 5.0
Arsenic and Antimony (as As)	<= 10 ppb	< 10
Trace Impurities –Barium (Ba)	<= 20.0 ppb	< 1.0
Trace Impurities –Beryllium (Be)	<= 100.0 ppb	< 1.0
Trace Impurities –Bismuth (Bi)	<= 100.0 ppb	< 10.0
Trace Impurities –Boron (B)	<= 10.0 ppb	< 5.0
Trace Impurities –Cadmium (Cd)	<= 20.0 ppb	< 1.0
Trace Impurities –Calcium (Ca)	<= 50.0 ppb	1.0
Trace Impurities –Chromium (Cr)	<= 20.0 ppb	< 1.0
Trace Impurities –Cobalt (Co)	<= 20.0 ppb	< 1.0
Trace Impurities –Copper (Cu)	<= 10.0 ppb	< 1.0
Trace Impurities –Gallium (Ga)	<= 50.0 ppb	< 1.0
Trace Impurities –Germanium (Ge)	<= 50.0 ppb	< 10.0
Trace Impurities –Gold (Au)	<= 20.0 ppb	< 5.0
Heavy Metals (as Pb)	<= 200 ppb	< 100

Test	Specification	Result
Trace Impurities –Iron (Fe)	≤ 50.0 ppb	< 1.0
Trace Impurities –Lead (Pb)	≤ 20.0 ppb	< 10.0
Trace Impurities –Lithium (Li)	≤ 50.0 ppb	< 1.0
Trace Impurities –Magnesium (Mg)	≤ 20.0 ppb	< 1.0
Trace Impurities –Manganese (Mn)	≤ 15.0 ppb	< 1.0
Trace Impurities –Molybdenum (Mo)	≤ 100.0 ppb	< 5.0
Trace Impurities –Nickel (Ni)	≤ 10.0 ppb	< 5.0
Trace Impurities –Niobium (Nb)	≤ 100.0 ppb	< 1.0
Trace Impurities –Potassium (K)	≤ 100.0 ppb	< 10.0
Trace Impurities –Silicon (Si)	≤ 50.0 ppb	< 10.0
Trace Impurities –Silver (Ag)	≤ 20.0 ppb	< 1.0
Trace Impurities –Sodium (Na)	≤ 100.0 ppb	< 5.0
Trace Impurities –Strontium (Sr)	≤ 20.0 ppb	< 1.0
Trace Impurities –Tantalum (Ta)	≤ 100.0 ppb	< 5.0
Trace Impurities –Thallium (Tl)	≤ 10.0 ppb	< 5.0
Trace Impurities –Tin (Sn)	≤ 100.0 ppb	< 10.0
Trace Impurities –Titanium (Ti)	≤ 20.0 ppb	< 1.0
Trace Impurities –Vanadium (V)	≤ 100.0 ppb	< 1.0
Trace Impurities –Zinc (Zn)	≤ 50.0 ppb	< 1.0
Trace Impurities –Zirconium (Zr)	≤ 100.0 ppb	< 1.0
Particle Count –0.2 µm and greater	≤ 5000 par/ml	83
Particle Count –0.3 µm and greater	≤ 5000 par/ml	15
Particle Count –0.5 µm and greater	≤ 50 par/ml	3
Particle Count –1.0 µm and greater	≤ 8 par/ml	1

For Microelectronic Use

Storage Conditions:

Country of Origin: US

Packaging Site: Paris Mfg Ctr & DC

ISO

Phillipsburg, NJ 9001.2008, 14001.2004
 Paris, KY 9001.2008
 Mexico city, Mexico 9001.2008
 Deventer, The Netherlands 9001.2008, 14001.2004
 Selangor, Malaysia 9001.2008
 Panoli, India 9001.2008
 Gliwice, Poland 9001.2008, 17025.2005



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